

ABSTRACT OF THE DISCLOSURE

A sorting section can be supplied with parts from plurality of supply sources. A semiconductor device sorting system is provided with a sorting section for sorting good transistors by means of an electric performance test thereof and supply sections adapted to separate the transistor parts that are collectively supplied in a complex into transistors and supply the separated transistors to the sorting section. An appropriate one of the supply sections can be selected corresponding to the supply form of the transistor parts to be separated. A selected supply section can be switched to another depending on the supply form of the transistor parts.

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